Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/609,452	HE ET AL.
Examiner	Art Unit
Paul D. Kim	3729

SEARCHED				
Class	Subclass	Date	Examiner	
29	592.1 605 830-832 846 854	10/20/2005	PK	
174	52.1 255			
	260 261			
607	1-3 46-52			
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600	302 554 377	/		
127	877	V		

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	DATE	EXMR
Text Search EAST/NPL (IEEE)	10/26/2005	PK
Updated Text Search East	4/5/2006	PK
Updated Text Search EAST/PGPub	6/9/2006	PK
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